

Serial No. 09/935,012

PATENT  
Docket No. 58027-011500**AMENDMENTS TO THE CLAIMS**

**Claim 1 (currently amended):** A distributed Bragg reflector for use in a vertical cavity surface emitting laser, comprising a group of layers of semiconductor material doped to reduce voltage drop and optical loss in a vertical cavity surface emitting laser, ~~wherein in the group of layers there are~~ further including alternating layers of an InP compound approximately lattice-matched with ~~and layers comprising~~  $\text{Al}_a\text{Ga}_{1-a}\text{As}_b\text{Sb}_{1-b}$ , where "a" and "b" indicate relative proportions of ~~atoms of an antimonide (Sb) compound, at least some of the alternating layers having Sb also including the elements arsenic, aluminum, and gallium.~~

**Claim 2 (original):** The distributed Bragg reflector of claim 1, wherein the group of layers of semiconductor material are epitaxially grown on a substrate.

**Claim 3 (original):** The distributed Bragg reflector of claim 2, wherein the substrate includes indium phosphide (InP).

**Claim 4 (cancelled)**

**Claim 5 (currently amended):** The distributed Bragg reflector of claim[[ 4]] 1, wherein "a" is greater than 0.9 in one layer of the alternating layer pairs and less than 0.9 in another layer of the alternating layer pairs.

**Claim 6 (currently amended):** The distributed Bragg reflector of claim[[ 4]] 1, wherein "a" is less than 0.3 in one layer of the alternating layer pairs and greater than 0.3 in another layer of the alternating layer pairs.

**Claim 7 (currently amended):** The distributed Bragg reflector of claim[[ 4]] 1, wherein "a" is less than 0.3 in one layer of the alternating layer pairs and greater than 0.9 in another layer of the alternating layer pairs.

**Claim 8 (currently amended):** The distributed Bragg reflector of claim[[ 4]] 1, wherein "a" is less than 0.3 in one layer of the alternating layer pairs and "a" is large enough such that the layer is substantially transparent to lasing light.

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**Claim 9 (original):** The distributed Bragg reflector of claim 2, wherein the substrate is n-doped with the element selenium (Se).

**Claim 10 (original):** The distributed Bragg reflector of claim 1, wherein the group of layers of semiconductor material are configured to form a reflective device.

**Claim 11 (original):** The distributed Bragg reflector of claim 10, wherein the reflective device is n-doped using tellurium.

**Claim 12 (currently amended):** A device for reflecting light to an active region in a vertical cavity surface emitting laser, comprising:

a mirror portion including the element antimony (Sb) and an indium phosphide (InP) compound epitaxially grown on a substrate wherein in the mirror portion there are a group of layers, the group of layers further including alternating layers of an InP compound approximately lattice-matched with layers comprising  $\text{Al}_a\text{Ga}_{1-a}\text{As}_b\text{Sb}_{1-b}$ , where "a" and "b" indicate relative proportions of atoms~~said group of layers being alternating layers of the InP compound and layers of the antimonide (Sb) compound~~, and wherein electric current is pumped through the group of layers forming the mirror portion to electrically pump the active region.

**Claim 13 (original):** The device of claim 12, wherein the substrate includes indium phosphide (InP).

**Claim 14 (original):** The device of claim 13, wherein the substrate is n-doped with the element selenium (Se).

**Claim 15 (original):** The device of claim 12, wherein the mirror portion is n-doped to reduce voltage drop and optical loss in a vertical cavity surface emitting laser.

**Claim 16 (original):** The device of claim 15, wherein the mirror portion is n-doped using tellurium.

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**Claim 17 (currently amended):** A vertical cavity surface emitting laser, comprising:

a pair of mirror portions epitaxially grown on a substrate, the pair of mirror portions including a group of layered stacks of paired semiconductor material, wherein the pair of mirror portions are n-doped to reduce voltage drop and optical loss;

the group of layered stacks in each of the mirror portions further including alternating layers of an InP compound approximately lattice-matched with layers comprising  $\text{Al}_a\text{Ga}_{1-a}\text{As}_b\text{Sb}_{1-b}$ , where "a" and "b" indicate relative proportions of atoms;

~~wherein each of the pair of mirror portions includes at least one of the element antimony (Sb) and the compound indium phosphide (InP);~~

~~wherein in each of the pair of mirror portions there are a group of layers, said group of layers being alternating layers of an InP compound and layers of an antimonide (Sb) compound;~~

an active region epitaxially grown on the substrate and positioned between the pair of mirror portions;

a doped tunnel junction configured to provide electron-hole conversion from one of the pair of mirror portions; and

wherein the pair of mirror portions, the active region, and the tunnel junction are epitaxially grown on the substrate in a single step, and wherein electric current is pumped through the pair of mirror portions to electrically pump the active region.

**Claim 18 (original):** The vertical cavity surface emitting laser of claim 17, wherein the substrate includes indium phosphide (InP).

**Claim 19 (cancelled)**

**Claim 20 (currently amended):** The distributed Bragg reflector of claim 17-19, wherein "a" is greater than 0.9 in one layer of the alternating layer pairs and less than 0.9 in another layer of the alternating layer pairs.

**Claim 21 (currently amended):** The distributed Bragg reflector of claim 17-19, wherein "a" is less than 0.3 in one layer of the alternating layer pairs and greater than 0.3 in another layer of the alternating layer pairs.

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**Claim 22 (currently amended):** The distributed Bragg reflector of claim 17-19, wherein "a" is less than 0.3 in one layer of the alternating layer pairs and greater than 0.9 in another layer of the alternating layer pairs.

**Claim 23 (currently amended):** The distributed Bragg reflector of claim 17-19, wherein "a" is less than 0.3 in one layer of the alternating layer pairs and "a" is large enough such that the layer is substantially transparent to lasing light.

**Claim 24 (original):** The vertical cavity surface emitting laser of claim 17, wherein the substrate is n-doped with the element selenium (Se).

**Claim 25 (original):** The vertical cavity surface emitting laser of claim 17, wherein the doped tunnel junction is n-doped with silicon (Si).

**Claim 26 (original):** The vertical cavity surface emitting laser of claim 17, wherein the doped tunnel junction is p-doped with CBr4.

**Claim 27 (original):** The vertical cavity surface emitting laser of claim 17, wherein the pair of mirror portions include a first mirror portion positioned on a top of the active region and a second mirror portion positioned below the active region.

**Claim 28 (original):** The vertical cavity surface emitting laser of claim 27, wherein the first and second mirror portions are n-doped using tellurium.

**Claim 29 (original):** The vertical cavity surface emitting laser of claim 17, wherein the active region is grown to include a cavity having five strain compensated quantum wells, the quantum wells including the elements aluminum, indium, gallium, and arsenic.

**Claim 30 (original):** The vertical cavity surface emitting laser of claim 17, wherein the VCSEL operates in the approximate range from between 1.3 microns and 1.6 microns.

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**Claim 31 (currently amended):** A vertical cavity surface emitting laser comprising:

a substrate on which a pair of mirror portions, an active region, and a tunnel junction are epitaxially grown in a single step in which semiconductor elements are deposited to form a multi-layered structure;

~~wherein in each of the pair of mirror portions there are a group of layers, said group of layers being alternating layers of an InP compound and layers of an antimonide (Sb) compound;~~

the multi-layered structure in each of the mirror portions further including alternating layers of an InP compound approximately lattice-matched to layers comprising  $\text{Al}_a\text{Ga}_{1-a}\text{As}_b\text{Sb}_{1-b}$ , where "a" and "b" indicate relative proportions of atoms; and

at least one metal contact disposed on the substrate, wherein electric current is pumped through the pair of mirror portions to electrically pump the active region.

**Claim 32 (original):** The vertical cavity surface emitting laser of claim 21, wherein the substrate includes indium phosphide (InP).

**Claim 33 (cancelled)**

**Claim 34 (currently amended):** The distributed Bragg reflector of claim ~~31-33~~, wherein "a" is greater than 0.9 in one layer of the alternating layer pairs and less than 0.9 in another layer of the alternating layer pairs.

**Claim 35 (currently amended):** The distributed Bragg reflector of claim ~~31-33~~, wherein "a" is less than 0.3 in one layer of the alternating layer pairs and greater than 0.3 in another layer of the alternating layer pairs.

**Claim 36 (currently amended):** The distributed Bragg reflector of claim ~~31-33~~, wherein "a" is less than 0.3 in one layer of the alternating layer pairs and greater than 0.9 in another layer of the alternating layer pairs.

**Claim 37 (currently amended):** The distributed Bragg reflector of claim ~~31-33~~, wherein "a" is less than 0.3 in one layer of the alternating layer pairs and "a" is large enough such that the layer is substantially transparent to lasing light.

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**Claim 38 (original):** The vertical cavity surface emitting laser of claim 31, wherein the substrate is n-doped with the element selenium (Se).

**Claim 39 (original):** The vertical cavity surface emitting laser of claim 31, wherein the doped tunnel junction is n-doped with silicon (Si).

**Claim 40 (original):** The vertical cavity surface emitting laser of claim 31, wherein the doped tunnel junction is p-doped with CBr<sub>4</sub>.

**Claim 41 (original):** The vertical cavity surface emitting laser of claim 31, wherein the VCSEL operates in the approximate range from between 1.3 microns and 1.6 microns.

**Claim 42 (original):** The vertical cavity surface emitting laser of claim 31, wherein the pair of mirror portions include a first mirror portion positioned on a top of the active region and a second mirror portion positioned below the active region.

**Claim 43 (currently amended):** A distributed Bragg reflector for use in a vertical cavity surface emitting laser, comprising a group of layers of semiconductor material doped ~~to reduce voltage drop and optical loss~~ to increase thermal conductivity in a vertical cavity surface emitting laser, the group of layers further including alternating layers of an InP compound approximately lattice-matched to layers comprising Al<sub>a</sub>Ga<sub>1-a</sub>As<sub>b</sub>Sb<sub>1-b</sub>, where "a" and "b" indicate relative proportions of atoms ~~wherein in the group of layers there are alternating layers of an InP compound and layers of an antimonide (Sb) compound, and wherein the group of layers are substantially lattice-matched to an InP substrate.~~

**Claim 44 (original):** The distributed Bragg reflector according to claim 43, wherein the element Sb and the compound InP are included in alternating layers.

**Claim 45 (original):** The vertical cavity surface emitting laser according to claim 17, wherein the element Sb and the compound InP are included in alternating layers.

**Claim 46 (original):** The vertical cavity surface emitting laser according to claim 31, wherein the element Sb and the compound InP are included in alternating layers.